

Search Notes



Application/Control No.

10/617,225

Examiner

HUY T. NGUYEN

Applicant(s)/Patent under Reexamination

OZAWA ET AL.

Art Unit

2621

SEARCHED

Class	Subclass	Date	Examiner
386	46	3/16/07	HN
↓	95	↓	↓
↓	112	↓	↓
↓	125	↓	↓
715	800	↓	↓
345	660	↓	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Fast search	3/16/07	HN